

Non-linear structure identification of a fed-batch bakers' yeast process - a simulation study of two techniques

Keulers, M.; **Sepp, K.**; Breur, A.; Reyman, G. Automation, simulation & measurement. Section A, Automation. Section M, Measurement : 3rd biennal conference : Tallinn, Estonia, October 7-11, 1991 = Automatiseerimine, modelleerimine ja mõõtmine : 3. rahvusvaheline konverents / Tallinna Tehnikaülikool 1992 / p. 82-87: ill https://www.esther.ee/record=b1064034*est